



DEFENSE TEST, EVAL, AND ACQUISITION: HOW TO MAKE IT BETTER

VADM Joe Dyer

Commander, Naval Air Systems Command

PANEL MEMBERS

Mr. Lee Frame, Acting Director, Operational Test & Evaluation, OSD

RADM Bob Besal, Commander Operational Test and Evaluation Force

Mr. Walter Hollis, Deputy Under Secretary of the Army for Operations Research

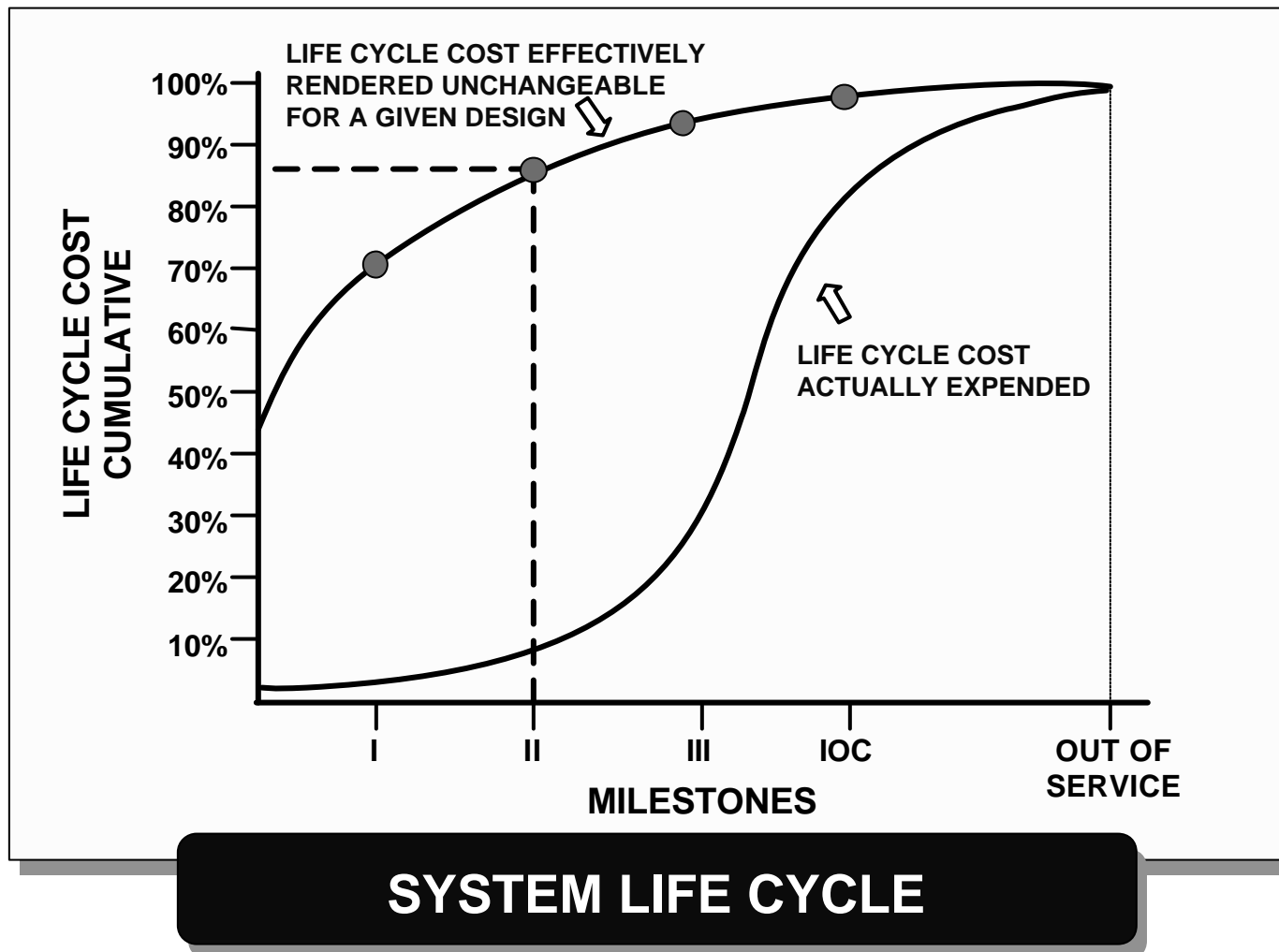
Mr. Richard Lockhart, Deputy Director OUSD(AT&L)S&T/DT&E

Dr. Marion Williams, Chief Scientist/Technical Director USAF OTEC

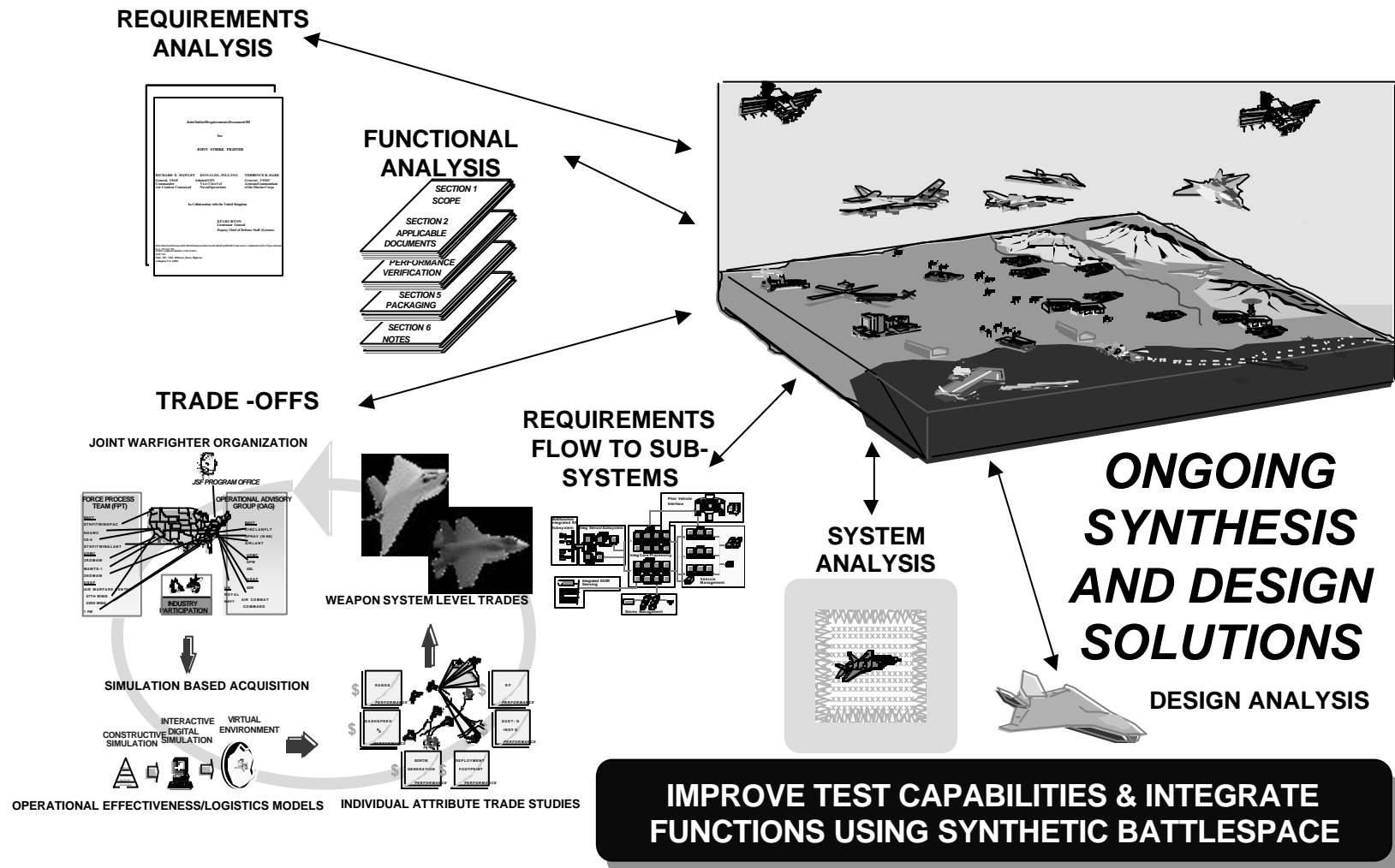
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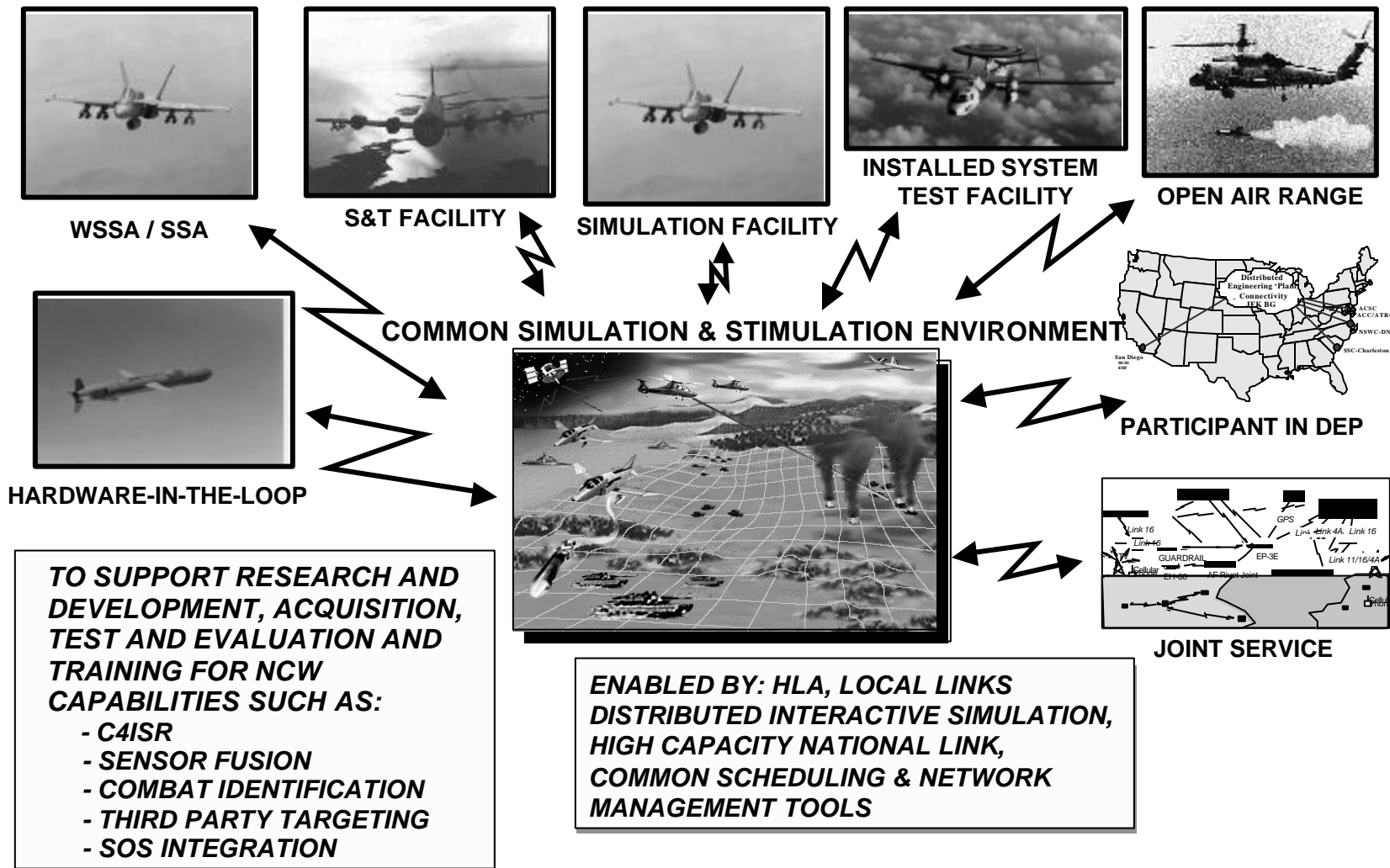
SYSTEMS ENGINEERING





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RDT&E NETWORK OF AVIATION FACILITIES REQUIRED



STRATEGIC INFLECTION

